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		ICES CITED BY	APPLICANT	Gary ESCHER, et al.		
				FILING DATE	GROUP	
				September 22, 2005 MAY 1 2 2006 M	2891	
		<del></del>	F	COUNTRY		
XAMINER		DOCUMENT		MADEMAN	TRANSI	LATION
INITIAL	l	NUMBER	DATE	COUNTRY	YES	NO
VY	AA	1 156 130	11/21/2001	Europe (in English)		
	AB	10-004083	01/06/1998	Japan (w/ English abstract and computer translation)	×	
	AC	2001-226773	08/21/2001	Japan (w/ English abstract; corresponding to US 2001/0003271 A1)		x
	AD	2000-303180	10/31/2000	Japan (w/ English abstract; corresponding to US 2003/0010446 A1)		x
-	AE	0 814 495	06/1997	Europe (in English)		
	AF	05-198532	08/1993	Japan (w/ English abstract and computer translation)	×	
_	AG	10-214819	08/1998	Japan (w/ English abstract and computer translation)	×	
<del>-   </del>	AH	2002-151473	05/2002	Japan (w/ English abstract; corresponding to US 2004/0035364 A1)		х
	Al	02/39495	05/16/2002	WIPO (w/ English abstract; corresponding to US 2004/0035364 A1)		×
$\dashv$	AJ	1 069 603	01/17/2001	Europe (in English)		
-	AK	07-245295	09/1995	Japan (w/ English abstract and computer translation)	×	
	AL	0 841 838	05/1998	Europe (in English)		
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-	AN	0 573 057	12/1993	Europe (in English)		
-	AO	2000-124197	04/28/2000	Japan (w/ English abstract and computer translation)	×	
	AP	1 081 749	07/03/2001	Europe (in English)		
	AQ	4-238882	08/1992	Japan (w/ certified English translation)	. х	
	AR	1-312087	12/1989	Japan (w/ English abstract; corresponding to US Patent 4,968,374)		×
<del></del>	AS	08-041309	02/1996	Japan (w/ English abstract and computer translation)		
	AT	08-081777	03/26/1996	Japan (w/ English abstract and computer translation)	·x	
	AU	08-268751	10/15/1996	Japan (w/ English abstract and computer translation)	x	
-+	AV	07-226378	08/22/1995	Japan (w/ English abstract and computer translation)	x	
	AW	64-039728	02/1989	Japan (w/ certified English translation)	×	·
	AX	03-115535	05/1991	Japan (w/ certified English translation)	×	
<del></del>	AY	05-117064	05/1993	Japan (w/ English abstract and corresponding to EP 0 508 731 filed		×
			<del> </del>	herewith)  Japan (w/ English abstract and computer translation)	×	Ή
_	AZ	05-238859	09/1993	Japan (w/ English abstract and computer translation)	×	_
	BA	06-057396	03/1994	Japan (w/ English abstract and computer translation)	×	+
<del></del>	BB	06-136505	05/1994 05/1994	Japan (w/ English abstract and computer translation)	×	+-
	BC	06-142822	05/1994	Japan (w/ English abstract and computer translation)	×	+
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	BE	07-176524	02/1996	Japan (w/ English abstract and computer translation)		1
	BF	08-037180	12/1996	Japan (w/ English abstract; corresponding to US Patent 5,919;332)	<del>                                     </del>	×
<del>_</del>	BG	08-339895 09-069554	03/1997	Japan (w/ English abstract; corresponding to US Patent 5,909,354)		×
VY	BH		10/1997	Japan (w/ English abstract; corresponding to US Patent 5,955,182)	<del>                                     </del>	x
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OMMERCE (Modified)	MERCE			ATTY DOCKET NO.					
OFFICE				277605US6YA PCT   10/550,215 APPLICANT					
LIST OF RE	FEREN	ICES CITED BY	APPLICANT	Gary ESCHER, et al.					
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			j	FOREIGN PATENT DOCUMENTS	S				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	(	TRANSLA YES			
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	AF	10-251871	09/1998	Japan (w/ English abstract; corresponding	to US Patent 6,120,640)		×		
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	Al	0 508 731	10/14/1992	Europe (in English)					
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	AK	11-233292	08/27/1999	Patent 6.783.863)  Japan (w/ English abstract and computer t	translation)	×			
	AL	11-312646	11/09/1999	Japan (w/ English abstract; corresponding			×		
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	AO	2 252 567	08/1992	Great Britain		<u> </u>			
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	AS	61-207566 07-058013 A	03/1995	Japan (English abstract and computer train	nslation)	×	<del>                                     </del>		
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INITIAL	AA	NUMBER 6,176,969	01/23/2001	Park et al.			J-333			
<del></del>	AB	5,919,332	07/06/1999	Koshiishi et al.		1				
<del></del>	AC		02/26/2004	Tomoyoshi et al.	· · · · · · · · · · · · · · · · · · ·	<del>    -                                  </del>	<del></del>			
	AD	5,366,585	11-1994	Robertson et al.			<del> </del>			
	AE	5,868,848	02-1999	Tsukamoto, Yuji		1				
<del></del>	AF	6,110,287	08-2000	Arai et al.						
<del></del>	AG	6,110,287	10-2000	Wicker et al.	<u> </u>					
<del></del>			07-2001	Tomoyasu et al.	<del></del>					
<del>                                     </del>	AΗ	6,264,788 6,394,026	07-2001	Wicker et al.		<del>- \</del> -	<b> </b>			
<b>———</b>	Al	<u> </u>	09-2002	Steger et al.		<del>                                     </del>				
<b></b>	AJ	6,444,083	09-2002	Morimoto, Tamotsu		<del>                                     </del>	ļ			
<b></b>	AK	6,514,377		Yen et al.		<del>                                     </del>	<b> </b>			
<b></b>	AL	6,527,911	03-2003	O'Donnell et al.		<del>                                     </del>	ļ			
	AM	6,533,910	03-2003			<del> </del>	<del></del>			
<b> </b>	AN	6,537,429	03-2003	O'Donnell et al.	·	<del>   </del>	<del> </del>			
<b>  -</b>	AO	6,544,380	04-2003	Tomoyasu et al.		<del> </del>	<del>}</del>			
	AP	6,583,064	06-2003	Wicker et al.		<del> </del>	<del>                                     </del>			
<b>  </b>	AQ	6,733,620	05-2001	Sugiyama et al.	<del>-</del>	<del>                                     </del>	<del>    -   -                              </del>			
<b></b>	AR	2002/0086501	07-2002	O'Donnell et al.		<del> </del>	H			
	-AS-	-2002/0086545-	07-2002	O'Donnell et al		<del> </del>	1			
	AT	2002/0086553	07-2002	O'Donnell et al.	<del></del>	<del> </del>	$\vdash$			
<b></b>	AU	2002/0142611	10-2002	O'Donnell et al.	····	<del> </del>	<del>                                     </del>			
<u> </u>	AV		05-2003	Long, Maolin	<del></del>	<del> </del>	+			
	AW	2004/0026372	02-2004	Takenaka et al.		<del> </del>	$\vdash$			
<b></b>	AX	2004/0060516	04-2004	Nishimoto et al.		<del> </del>	<del></del>			
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	вс	2004/0061447	04-2004	Saigusa et al.	·	<del> </del>	<del>                                     </del>			
	BD	2004/0063333	04-2004	Saigusa et al.		<del></del>	1			
VY	BE	2004/0125359	07-2004	Ludviksson et al.		1	<u> </u>			
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				FILING DATE		GROUP			
				September 22, 2005		2891			
			U.S	S. PATENT DOCUMENTS					
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VY	AA	6,894,769	05/2005	Ludviksson et al.	<b>\</b>				
	AB	6,875,477	04/2005	Trickett et al.					
	AC	6,852,433	02/2005	Maeda, Takao	1				
	AD	6,833,279	12/2004	Chol, Jin-Sik					
	AE	6,811,651	11/2004	Long, Maolin					
_	AF	6,806,949	10/2004	Ludviksson et al.	<b>\</b>		<del></del>		
	AG	6,805,952	10/2004	Chang et al.		<b>\</b>			
	AH	6,783,875	08/2004	Yamada et al.	<del>                                     </del>				
			08/2004	Sun et al.	<b></b>	<del>  \                                   </del>			
	AI	6,776,873	· · · · · · · · · · · · · · · · · · ·	O'Donnell et al.	<del> </del>	<del>                                     </del>			
	AJ	6,613,442	09/2003		<del>                                     </del>	-			
	AK	4,877,757	10/1989	York et al.		<del>- \</del>	· · · · · · · · · · · · · · · · · · ·		
_	AL	5,637,237	06/1997	Oehrlein et al.	<del>                                     </del>		<del>}</del>		
	AM	5,834,070	11/1998	Movchan et al.	<u> </u>		<del></del>		
	AN	6,296,740	10/2001	Xie et al.					
	AO	6,613,204	09/2003	Xie et al.	ļ	<u> </u>			
	AP	5,891,253	04/1999	Wong et al.			$\overline{}$		
	AQ	2004/0050495	03/2004	Sumiya et al.	ļ				
	AR	2004/0083970	05/2004	Imafuku et al.	ļ				
-	AS	5,885,356	03/1999	Zhao et al.		ļ			
	AT	2001/0050144	12/2001	Nishikawa et al.			· \		
	AU	5,902,763	05/1999	Waku et al.	<u> 1</u>				
	AV	5,423,936	06/1995	Tomita et al.					
	AW	6,554,906	04/2003	Kuibira, et al.					
	AX	6,266,133	07/2001	Miyajima, et al.					
VY	AY	2004/0168640A1	09/2004	Muto, et al.					
	1	OTHER R	EFERENCES	(Including Author, Title, Date, Pertinen	t Pages, e	itc.)			
VY	AZ	Production drawin	g for Depos	ition Shield, Upper believed to be	sold in	the U.S.	on April 12, 2000.		
			<del></del>	War Object Baltanada barata i	Abo II O		Saalambar 20		
VY BA		Production drawing for Deposition Shield believed to be sold in the U.S. prior to September 30, 2001.							
VY	88	Production drawing for Upper Electrode believed to be sold in the U.S. prior to September 30, 2001							
VY	вс	UIS Using Series, "Spraying Techniques Manual.", p. 95 (Oct. 30, 1998 Association), with English Translation					se Standard		
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			U.S	. PATENT DOCUMENTS			
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VY	AA	4,842,683	06/1989	Cheng et al.			\
	AB	6,663,714	12/203	Mizuno et al.			1
	AC	6,726,801	04/2004	Ahn, Jae-Su			\
	AD	6,562,186	05-2003	Saito et al.	156	345.24	
	ΑE	5,885,402	03-1999	Esquibel, James	156	345.24	
	AF	2002/0177001	11-2002	Harada et al.	428	469	
	AG	5,521,790	05-1996	Ruckel et al.	361	234	
	AH	6,068,729	05-2000	Shrotriya, Ashish V.	156	345.26	
	Al	5,968,377	10-1999	Yuasa et al.			
	AJ	5,955,182	09/1999	Yasuda et al.			
	AK	6,364,949	4/2002	Or et al.	•		
	AL	5,911,852	6/1999	Katayama et al.			
	AM	5,074,456	12/1991	Degner et al.			
	AN	4,612,077	9/1986	Tracy et al.			
	AO	6,182,603	2/2001	Shang et al.			
1	AP	2003/0010446	1/2003	Kajiyama et al.			
	AQ	2001/0003271	6/2001	Otsuki			
	AR	2002/0076508	6/2002	Chiang et al.		<u> </u>	L
	AS	6,368,987	4/2002	Kopacz et al.			
	AT	2004/0072426	4/2004	Jung			<u> </u>
	AU	2005/0150866	07-2005	O'Donnell	216	067	
	AV	2003/0113479	06-2003	Fakuda et al.	427	569	
	AW	4,357,387	11-1982	George et al.	442	71	
	AX	5,925,228	07-1999	Panitz	204	484	
Ī	AY	5,892,278	07-1999	Horita	257	706	
	AZ	6,073,449	06-2000	Watanabe et al.	62	3.2	
	ВА	2005/0103275	02-2004	Sasaki et al.			
VY	вв	4,310,390	01-1982	Bradley et al.		<u> </u>	
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			U.S	. PATENT DOCUMENTS			
XAMINER		DOCUMENT	DATE	NAME	CLASS	SUB	FILING DATE
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VΫ́	AA	6,383,964	5/2002	Nakahara et al.	_1		
	AB	6,123,791	9/2000	Han et al.			
	AC	6,170,429	1/2001	Schoepp et al.			
	AD	6,096,161	8/2000	Kim et al.			
	AE	5,362,335	11/1994	Rungta			
	AF	5,952,060	9/1999	Ravi	$\perp \perp \perp$		
	AG	5,680,013	10/1997	Domfest et al.			
	АН	5,494,713	2/1996	Ootuki			
	AJ.	5,000,113	3/1991	Wang et al.		Λ	
	AK	5,334,462	8/1994	Vine et al.			
	AL	6,830,622	12/2004	O'Donnell et al.			
	АМ	6,335,293	1/2002	Luo et al.		1	
	AN	6,221,202	4/2001	Walko, II			
<del></del>	AO	5,900,064	5/1999	Kholodenko		1	
	AP	5,641,375	6/1997	Nitescu et al.			
$\dashv$	AQ	6,383,333	5/2002	Haino et al.		1	
	AR	6,590,660	7/2003	Jung et al.			
$\dashv$	AS	6,570,654	5/2003	Jung et al.			\
	.AT	6,519,037	2/2003	Jung et al.			
	AU	6,373,573	4/2002	Jung et al.			1
+	AV	6,246,479	6/2001	Jung et al.			\
	AW	5,851,343	12/1998	Hsu et al.		1	1
_	AX	6,210,486	4/2001	Mizukami et al.			1
+	AY	2002/0086118	7/2002	Chang et al.	_		
	AZ	2003/0029563	2/2003	Kaushal et al.		1	1
	ВА	4,593,007	6/1986	Novinski			1
_	ВВ	5,985,102	11/1999	Leiphart		1	
	BC	6,106,625	8/2000	Koal et al.	· ·		1
+	BD	6,123,804	9/2000	Babassi et al.		<u> </u>	<del>                                     </del>
	BE	6,265,757	7/2001	Brady et al.			1
	BF	6,143,646	11/2000	Wetzel			<u> </u>
-	BG	2002/0090464	7/2002	Jiang et al.		<b> </b>	<del>                                     </del>
-	ВН	4,469,619	9/1984	Ohno et al.		<u> </u>	1
	Ві	5,426,310	6/1995	Tamada et al.	_	t	<del>                                     </del>
	BJ	5,556,501	9/1996	Collins et al.		<b>†</b>	1
	ВК	5,614,055	3/1997	Fairbairn et al.	-	<del>                                     </del>	
4	BL	5,944,902	8/1999	Redeker et al.		<del> </del>	
VY	BM	5,994,662	11/1999	Murugesh	<del></del>	<del>                                     </del>	
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		AB	5,879,575	3/1999	Tepman et al.						
		AC	5,759,360	6/1998	Ngan et al.						
		Ą	5,798,016	8/1998	Oehrlein et al.						
		ΑE	6,139,983	10/2000	Ohashi et al.						
		AF	5,484,752	1/1996	Waku et al.	<u> </u>	<b>\</b>				
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				<u> </u>	Addition	onal References	sheet(s) attached				
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